

Absolute Maximum Ratings		Values	Units
Symbol	Conditions ¹⁾		
V _{CES}		600	V
V _{CGR}	R _{GE} = 20 kΩ	600	V
I _C	T _{case} = 25/75 °C	200 / 145	A
I _{CM}	T _{case} = 25/75 °C; t _p = 1 ms	400 / 290	A
V _{GES}		± 20	V
P _{tot}	per IGBT, T _{case} = 25 °C	700	W
T _J , (T _{stg})		−40 ... +150 (125)	°C
V _{isol}	AC, 1 min.	2500	V
humidity	IEC-EN 60721-3-3		
climate	DIN IEC 68 T.1	40/125/56	
Inverse Diode and FWD of type „GAL“ ⁽⁶⁾⁸⁾			
I _F = −I _C	T _{case} = 25/80 °C	130 / 90	A
I _{FM} = −I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	400 / 290	A
I _{FSM}	t _p = 10 ms; sin.; T _J = 150 °C	880	A
I ² t	t _p = 10 ms; T _J = 150 °C	3800	A ² s

Characteristics		min.	typ.	max.	Units
Symbol	Conditions ¹⁾				
V _{(BR)CES}	V _{GE} = 0, I _C = 4 mA	≥ V _{CES}	—	—	V
V _{GE(th)}	V _{GE} = V _{CE} , I _C = 3mA	4,5	5,5	6,5	V
I _{CES}	V _{GE} = 0 } T _J = 25 °C	—	0,2	0,4	mA
	V _{CE} = V _{CES} } T _J = 125 °C	—	5	—	mA
I _{GES}	V _{GE} = 20 V, V _{CE} = 0	—	—	300	nA
V _{CESat}	I _C = 100 A } V _{GE} = 15 V;	—	1,8(2,0)	—	V
V _{CESat}	I _C = 150 A } T _J = 25 (125) °C }	—	2,1(2,4)	2,5(2,8)	V
g _{fs}	V _{CE} = 20 V, I _C = 150 A	50	—	—	S
C _{CHC}	per IGBT	—	—	350	pF
C _{ies}	V _{GE} = 0	—	8400	—	pF
C _{oes}	V _{CE} = 25 V	—	1000	—	pF
C _{res}	f = 1 MHz	—	600	—	pF
L _{CE}		—	—	25	nH
t _{d(on)}	V _{CC} = 300 V	—	130	—	ns
t _r	V _{GE} = −15 V / +15 V ³⁾	—	65	—	ns
t _{d(off)}	I _C = 150 A, ind. load	—	450	—	ns
t _f	R _{Gon} = R _{Goff} = 10 Ω	—	40	—	ns
E _{on}	T _J = 125 °C	—	8,5	—	mWs
E _{off}		—	5,5	—	mWs
Inverse Diode and FWD of type „GAL“ ⁽⁶⁾⁸⁾					
V _F = V _{EC}	I _F = 100 A } V _{GE} = 0 V;	—	1,45(1,35)	1,7	V
	I _F = 150 A } T _J = 25 (125) °C }	—	1,55(1,55)	1,9	V
V _{TO}	T _J = 125 °C	—	—	0,9	V
r _t	T _J = 125 °C	—	6	8	mΩ
I _{RRM}	I _F = 150 A; T _J = 125 °C ²⁾	—	53	—	A
Q _{rr}	I _F = 150 A; T _J = 125 °C ²⁾	—	8,1	—	μC
Thermal characteristics					
R _{thjc}	per IGBT	—	—	0,18	°C/W
R _{thjc}	per diode	—	—	0,5	°C/W
R _{thch}	per module	—	—	0,05	°C/W

¹⁾ T_{case} = 25 °C, unless otherwise specified

²⁾ I_F = − I_C, V_R = 300 V,
−di_F/dt = 1500 A/μs, V_{GE} = 0 V

³⁾ Use V_{GEoff} = −5... −15 V

⁶⁾ The free-wheeling diode of the GAL type has the data of the inverse diode

⁸⁾ CAL = Controlled Axial Lifetime Technology

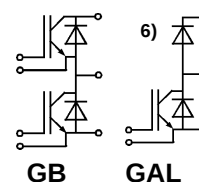
SEMITRANS® M Superfast NPT-IGBT Modules

SKM 145 GB 063 DN
SKM 145 GAL 063 DN

Preliminary Data



SEMITRANS 2N (low inductance)



Features

- N channel, homogeneous Silicon structure (NPT- Non punch-through IGBT)
- Low tail current with low temperature dependence
- High short circuit capability, self limiting if term. G is clamped to E
- Pos. temp.-coeff. of V_{CESat}
- Very low C_{ies}, C_{oes}, C_{res}
- Latch-up free
- Fast & soft inverse CAL diodes ⁸⁾
- Isolated copper baseplate using DCB Direct Copper Bonding Technology without hard mould
- Large clearance (10 mm) and creepage distances (20 mm)

Typical Applications

- Switching (not for linear use)
- Switched mode power supplies
- UPS
- AC inverter servo drives
- Pulse frequencies also above 10 kHz
- Welding inverters

Cases and mech. data → page 6

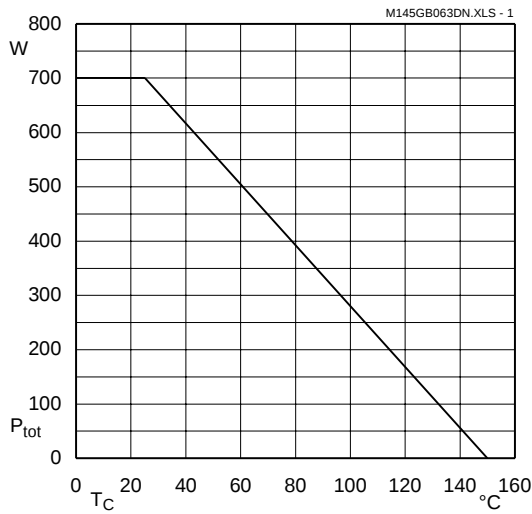


Fig. 1 Rated power dissipation $P_{tot} = f(T_C)$

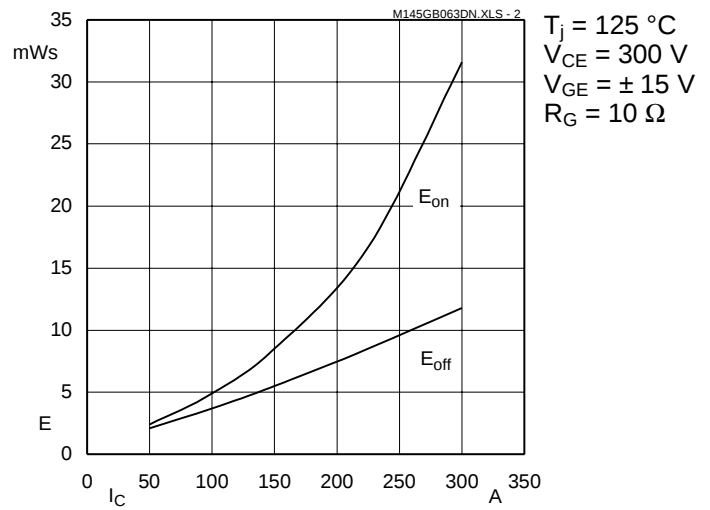


Fig. 2 Turn-on /-off energy $= f(I_C)$

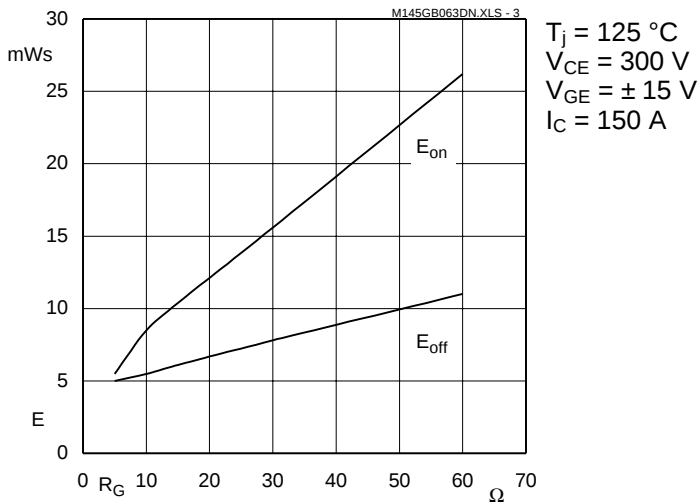


Fig. 3 Turn-on /-off energy $= f(R_G)$

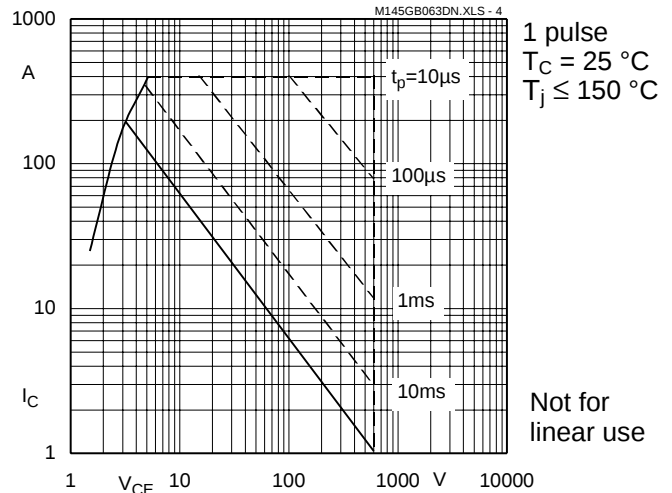


Fig. 4 Maximum safe operating area (SOA) $I_C = f(V_{CE})$

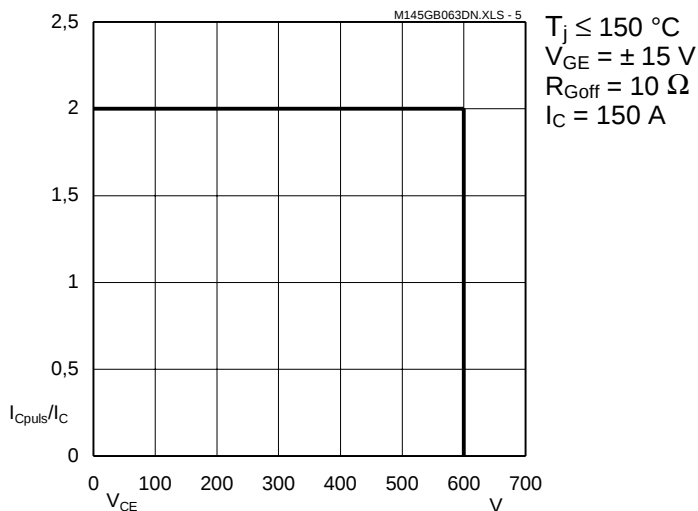


Fig. 5 Turn-off safe operating area (RBSOA)

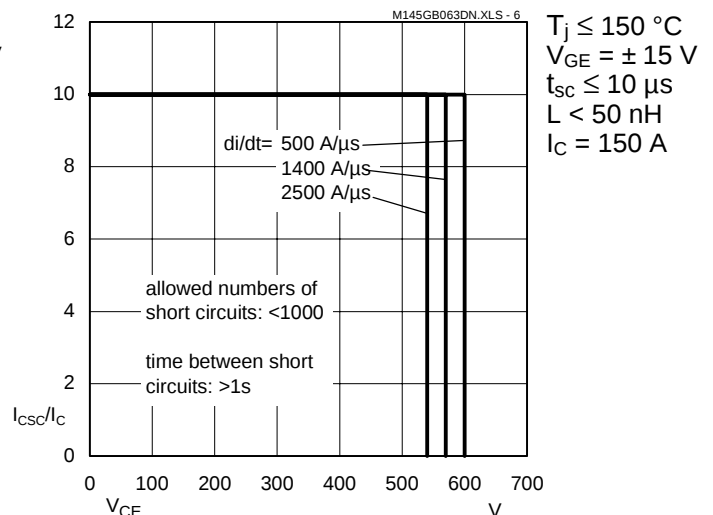


Fig. 6 Safe operating area at short circuit $I_C = f(V_{CE})$

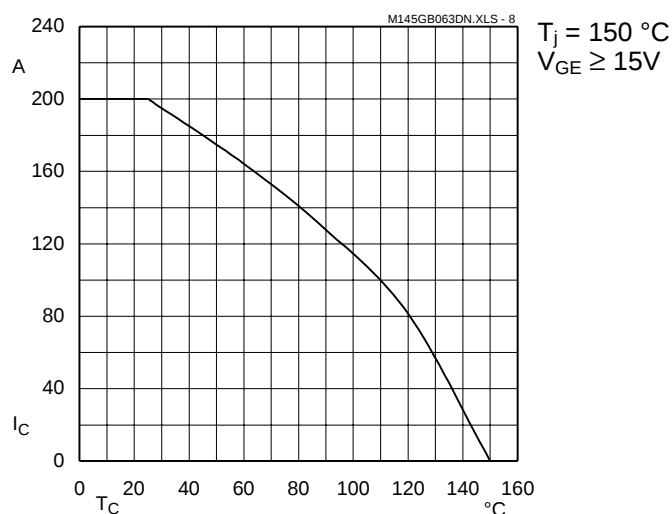


Fig. 8 Rated current vs. temperature $I_C = f(T_C)$

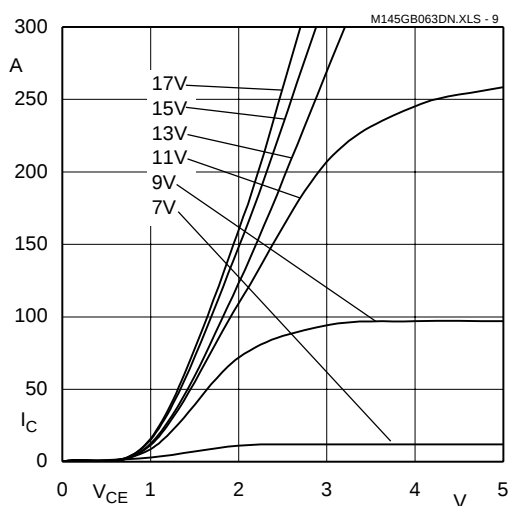


Fig. 9 Typ. output characteristic, $t_p = 250 \mu s$; $T_j = 25 \text{ } ^\circ\text{C}$

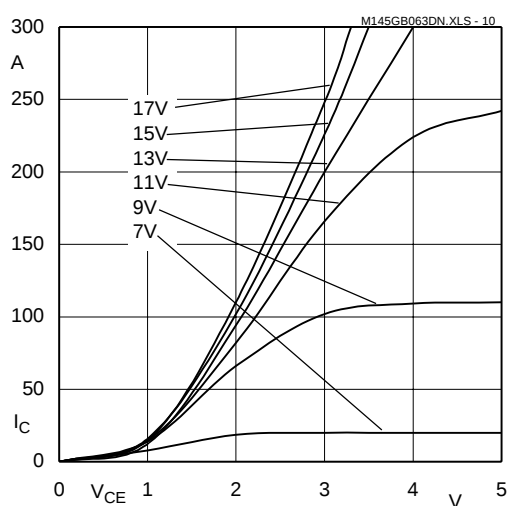


Fig. 10 Typ. output characteristic, $t_p = 250 \mu s$; $T_j = 125 \text{ } ^\circ\text{C}$

$$P_{\text{cond}}(t) = V_{\text{CEsat}}(t) \cdot I_C(t)$$

$$V_{\text{CEsat}}(t) = V_{\text{CE(TO)(Tj)}} + r_{\text{CE(Tj)}} \cdot I_C(t)$$

$$V_{\text{CE(TO)(Tj)}} \leq 1,2 - 0,001 (T_j - 25) \text{ [V]}$$

$$\text{typ.: } r_{\text{CE(Tj)}} = 0,006 + 0,000027 (T_j - 25) \text{ [}\Omega\text{]}$$

$$\text{max.: } r_{\text{CE(Tj)}} = 0,0090 + 0,000028 (T_j - 25) \text{ [}\Omega\text{]}$$

$$\text{valid for } V_{\text{GE}} = +15 \pm 2 \text{ [V]}; I_C \geq 0,3 I_{\text{Cn}}$$

Fig. 11 Saturation characteristic (IGBT)
Calculation elements and equations

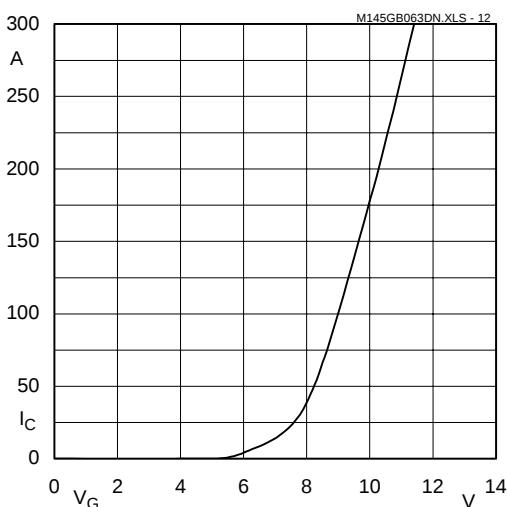
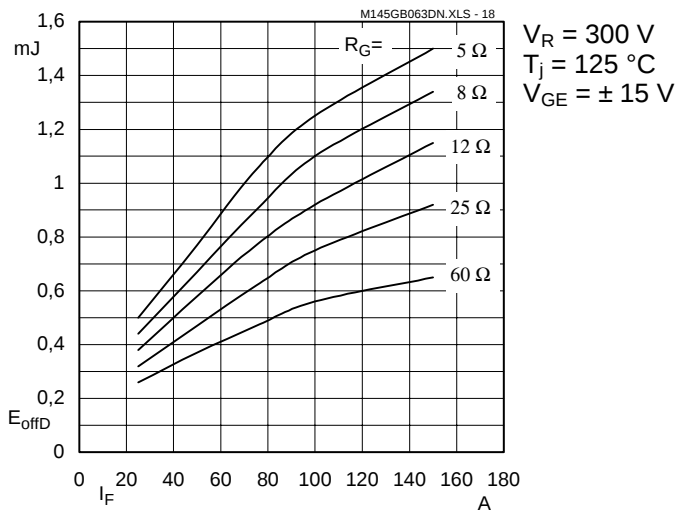
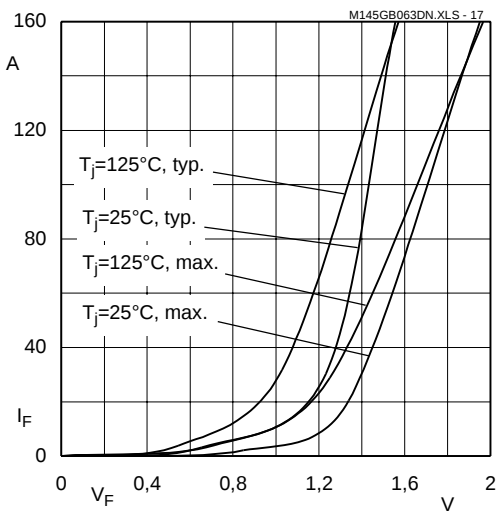
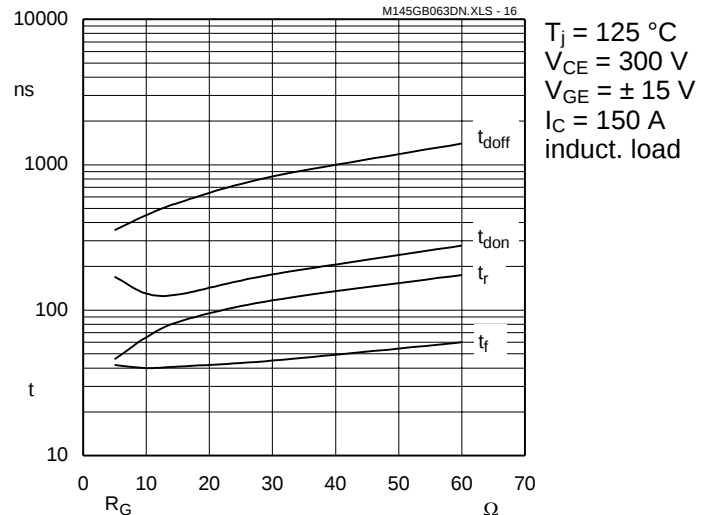
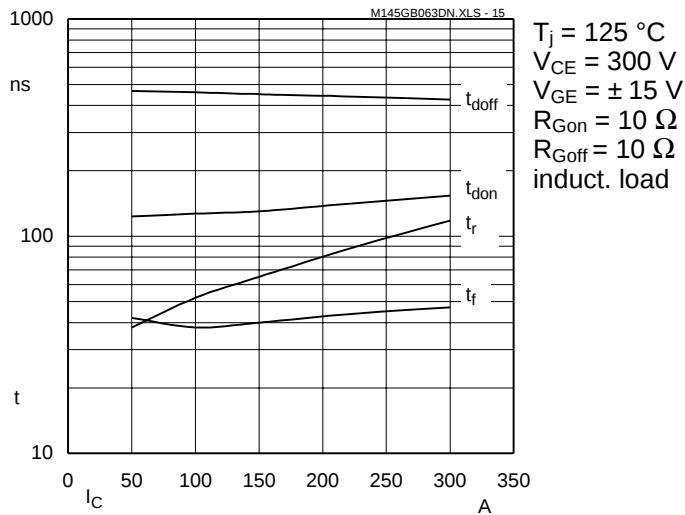
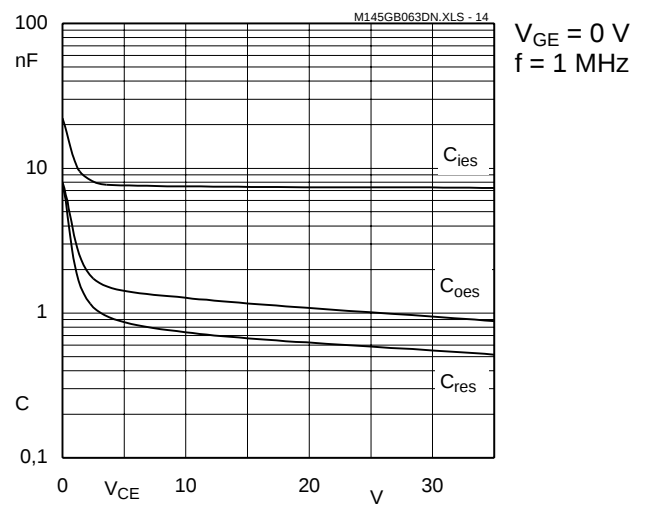
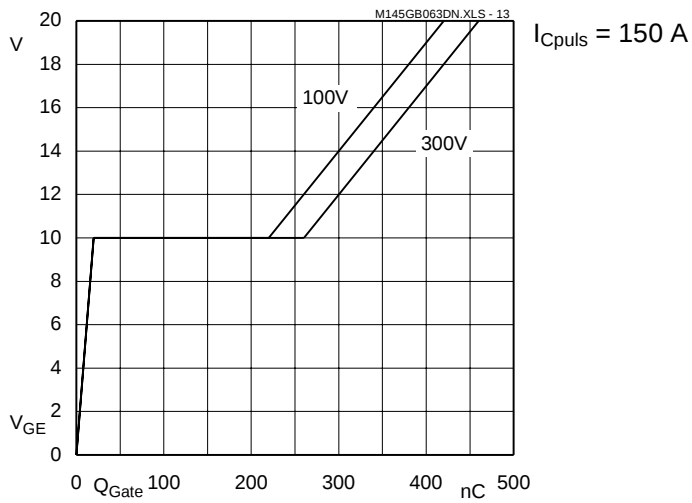


Fig. 12 Typ. transfer characteristic, $t_p = 250 \mu s$; $V_{\text{CE}} = 20 \text{ V}$



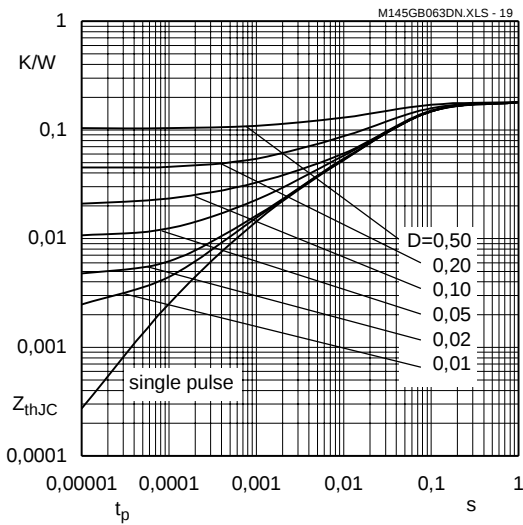


Fig. 19 Transient thermal impedance of IGBT
 $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

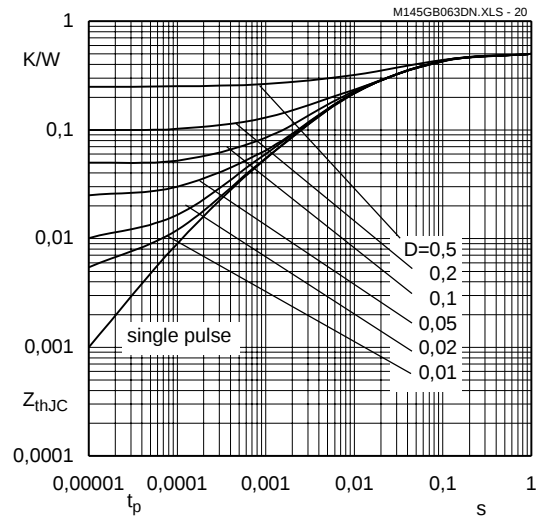


Fig. 20 Transient thermal impedance of inverse CAL diodes
 $Z_{thJC} = f(t_p)$; $D = t_p / t_c = t_p \cdot f$

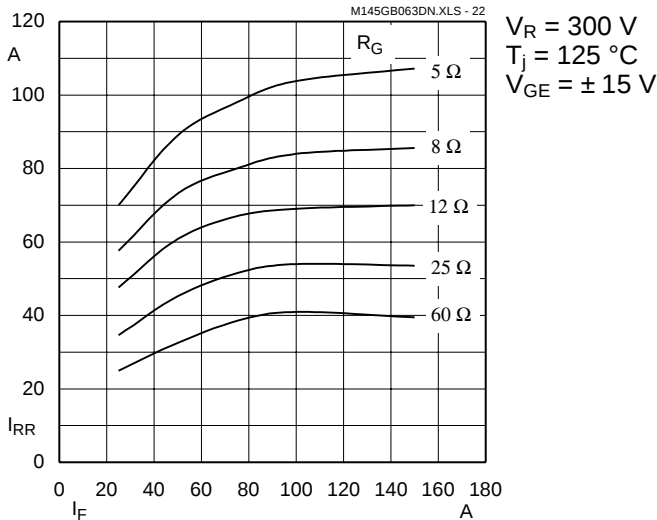


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F; R_G)$

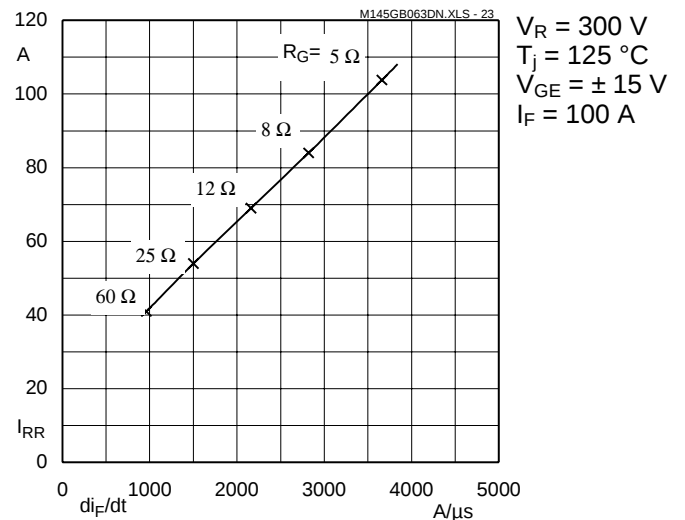


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(di/dt)$

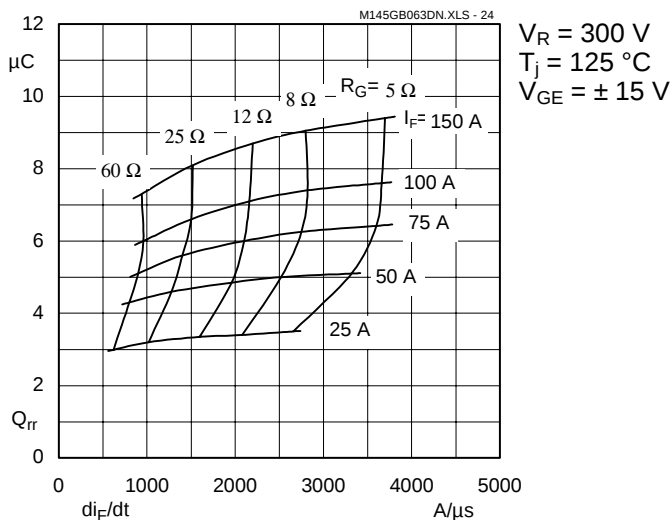
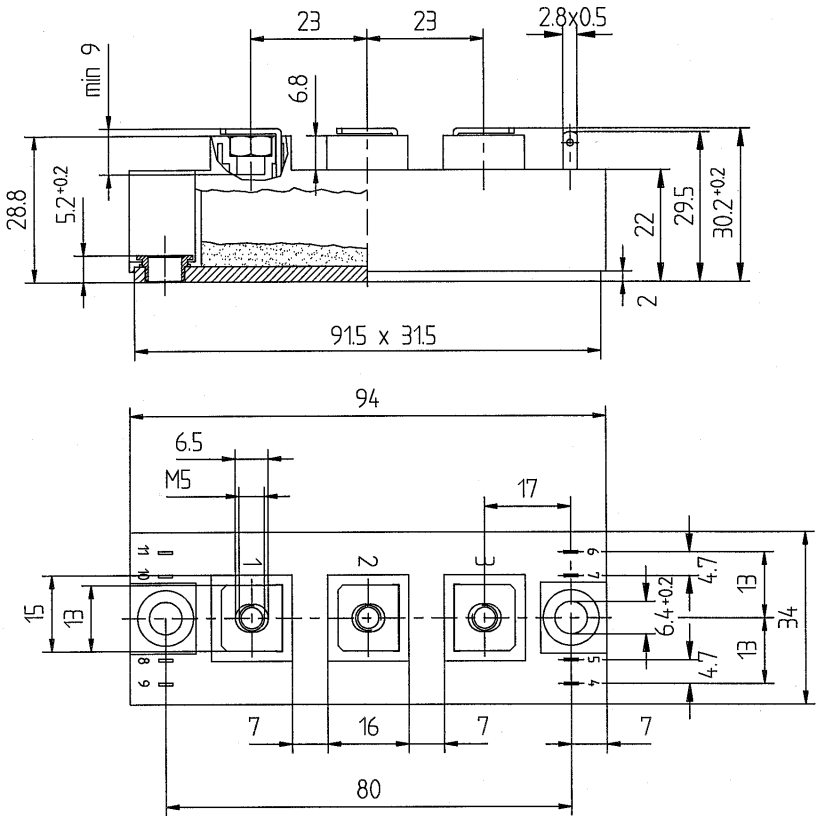
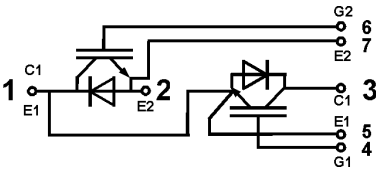


Fig. 24 Typ. CAL diode recovered charge

SEMITRANS 2N (low inductance)

Case D 93
UL Recognized
File no. E 63 532

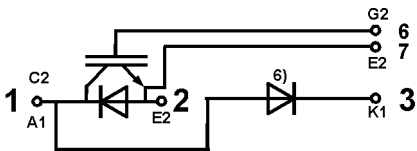
SKM 145 GB 063 DN



Dimensions in mm

SKM 145 GAL 063 DN

Case D 94 (→ D 93)



Case outline and circuit diagrams

Mechanical Data		Values			Units
Symbol	Conditions	min.	typ.	max.	
M ₁	to heatsink, SI Units(M6)	3	—	5	Nm
	to heatsink, US Units	27	—	44	lb.in.
M ₂	for terminals, SI Units(M5)	2,5	—	5	Nm
	for terminals, US Units	22	—	44	lb.in.
a		—	—	5x9,81	m/s ²
w		—	—	160	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Eight devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 2)

Larger packing units of 20 pieces are used if suitable

Accessories → SEMIKRON Book '99 page B 6 – 4

SEMIBOX → SEMIKRON Book '99 page C - 1.